

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/765,919	HATAKEYAMA ET AL.	
Examiner Sin J. Lee		Art Unit 1752	Page 1 of 1	

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*	C	US-2002/0132182 A1	09-2002	Nishi et al.	430/270.1
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NON-PATENT DOCUMENTS

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/	U	DERWENT English abstract for JP 2001-278918 (Hatakeyama et al).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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